

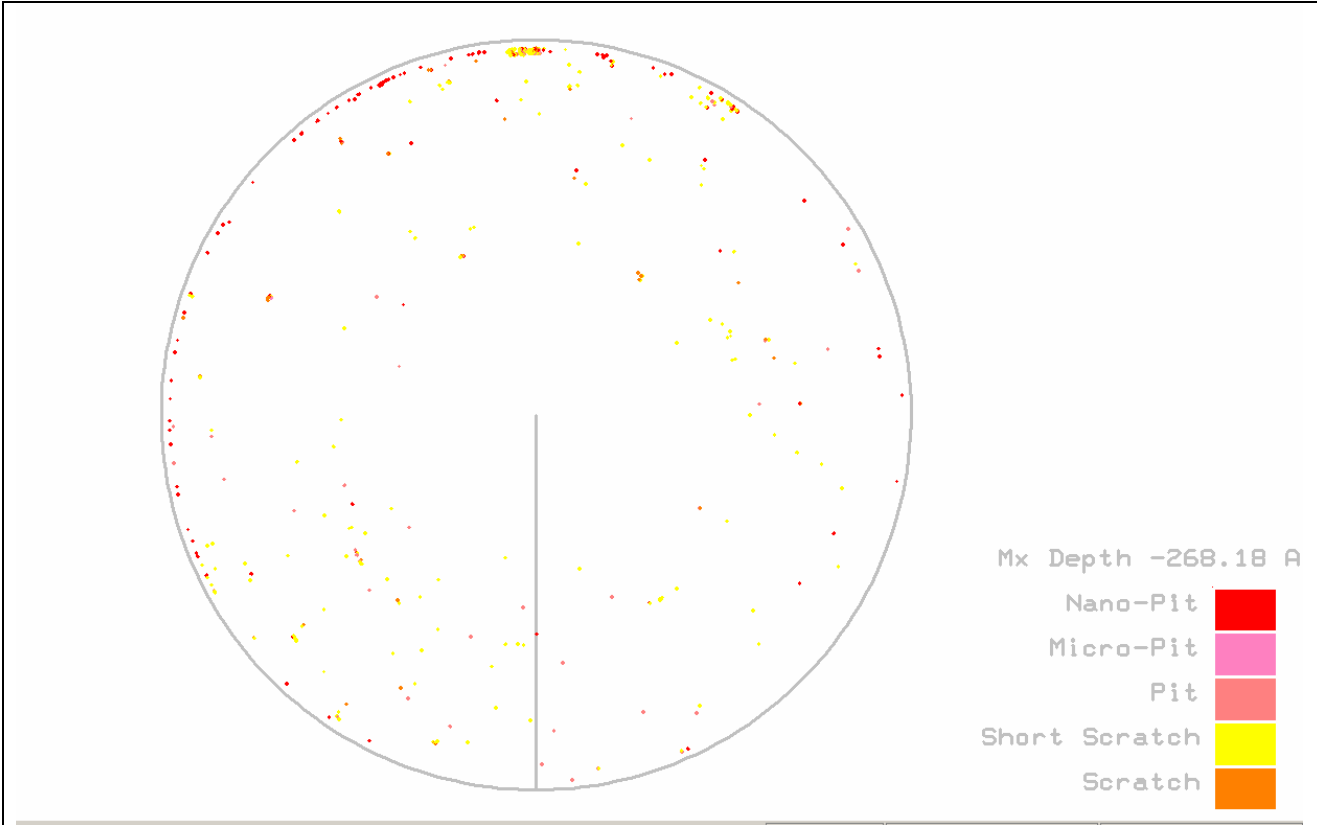
## Disk test threshold and defect repeatability.

The following defect plots show the effects of an increasingly more stringent test threshold.

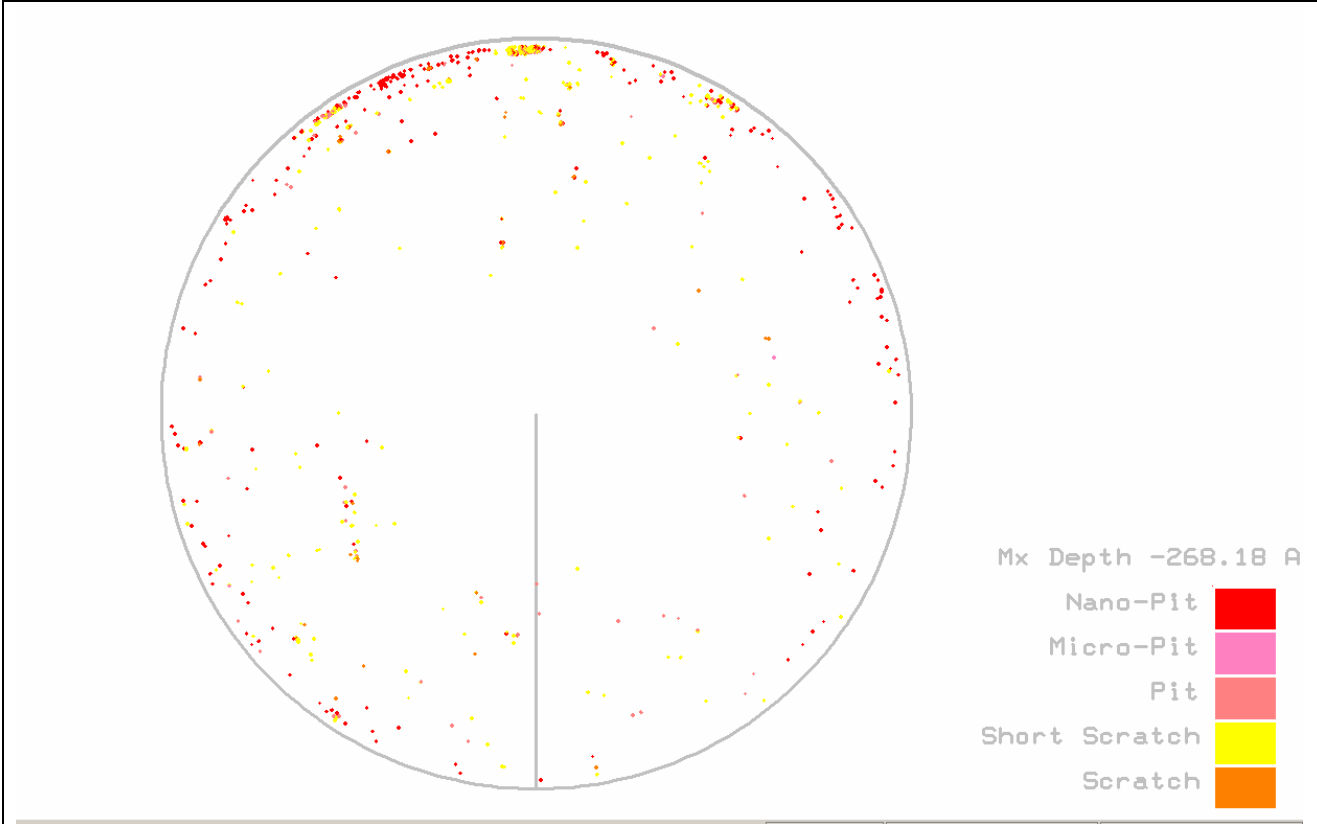
Two sets of plots are provided, one for nano-pits and another for nano-asperities.

The tool shows excellent repeatability and the two sets of plots are very characteristic of nano-asperities and nano-pits.

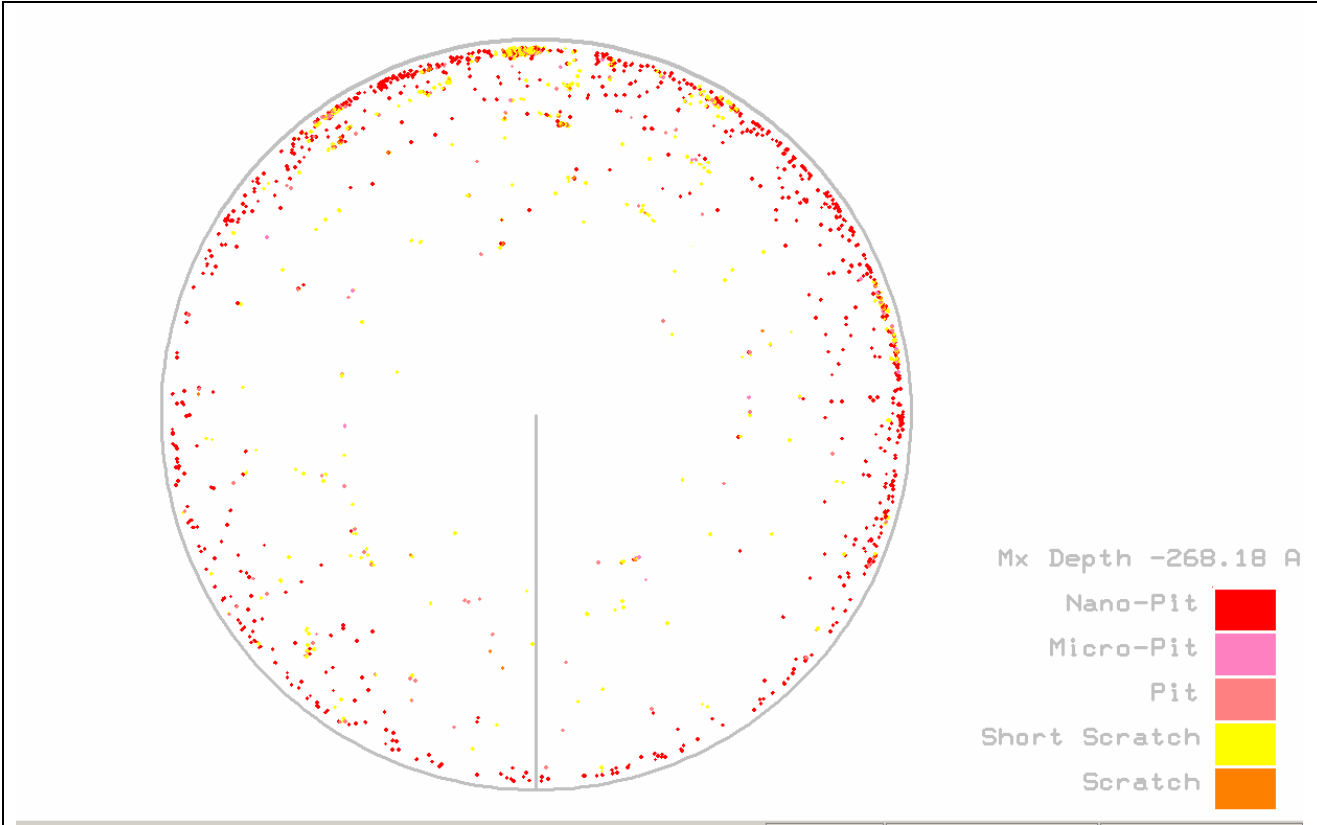
Nano-asperities typically are found concentrated at the disk outer diameter while nano-pits have a tendency to be more evenly distributed over the full disk surface.



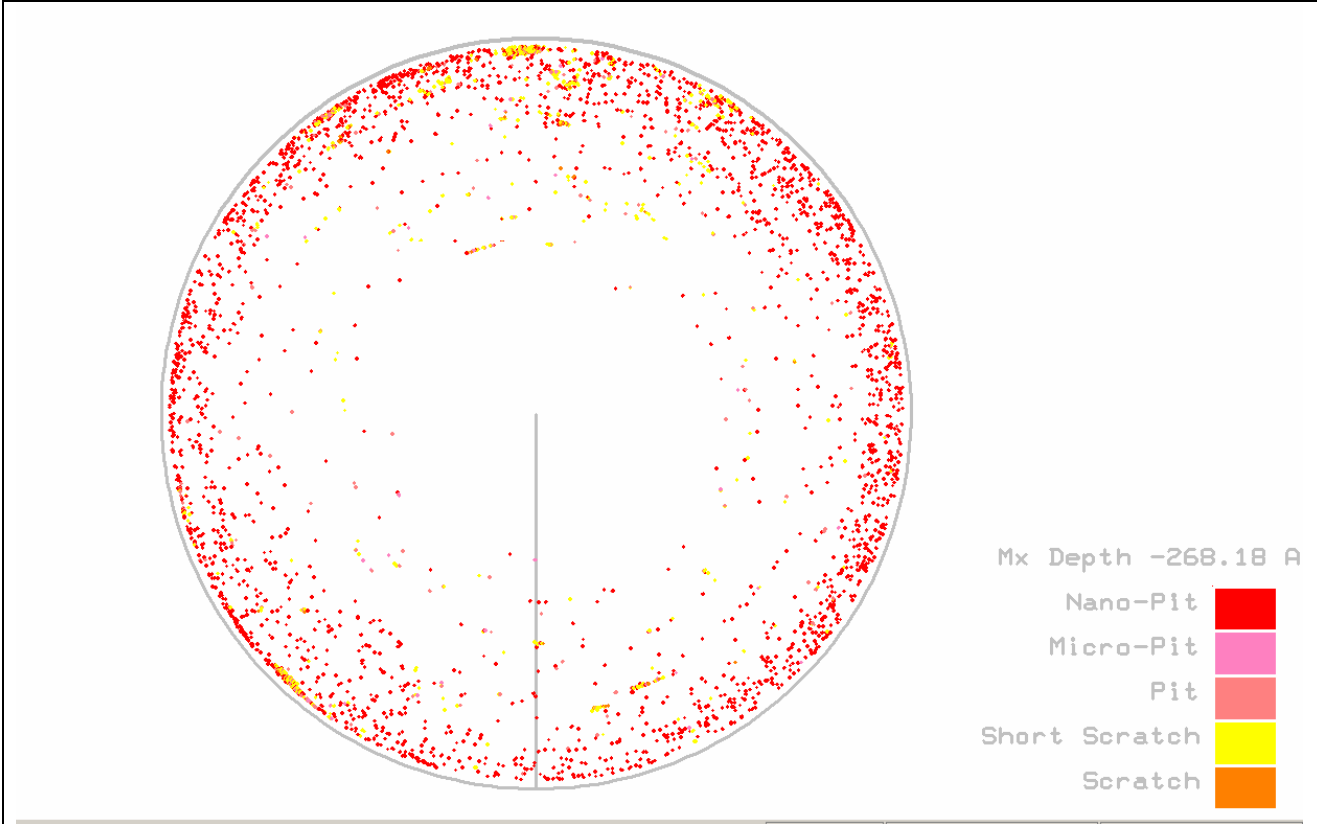
Nano-Pit Nano-Scan with Defects Deeper than 54 Angstroms



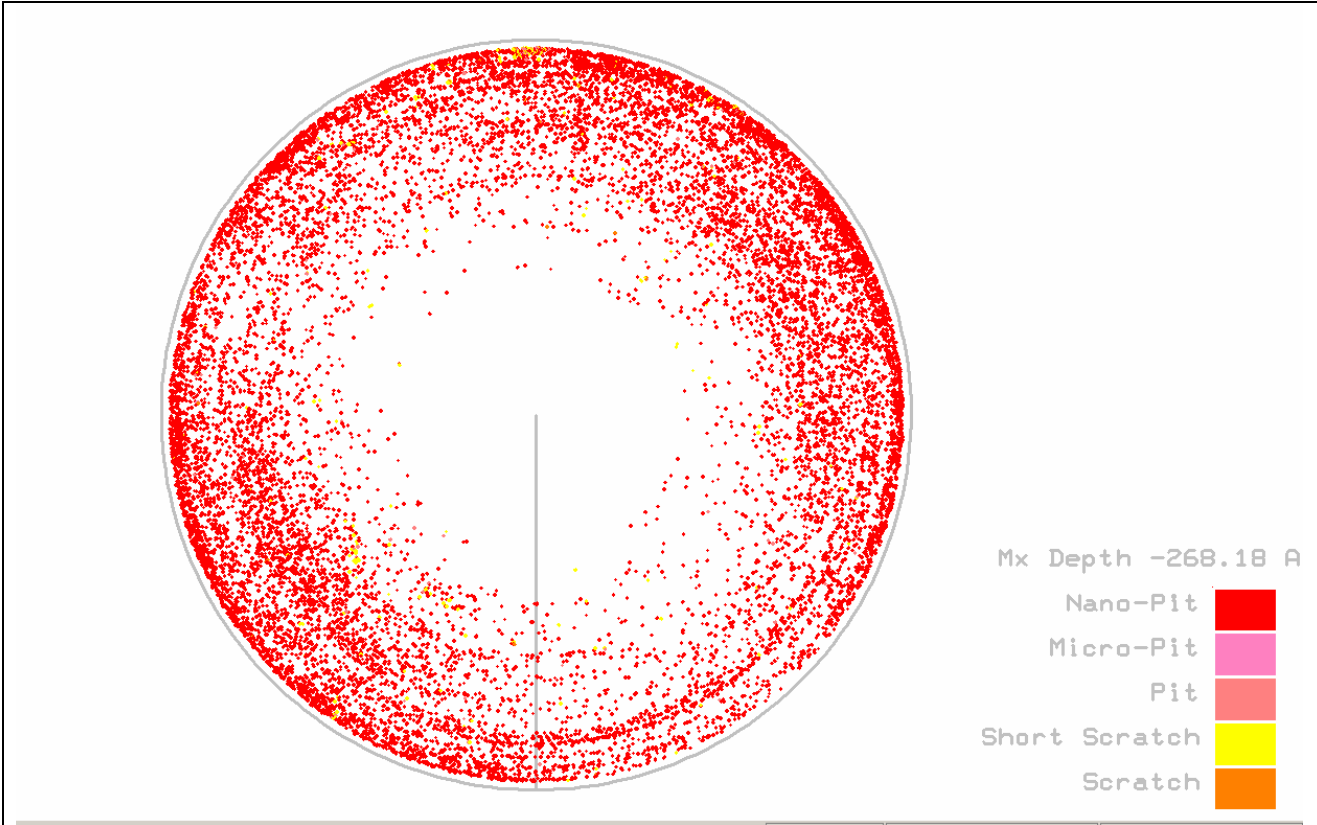
Nano-Pit Nano-Scan with Defects Deeper than 51 Angstroms



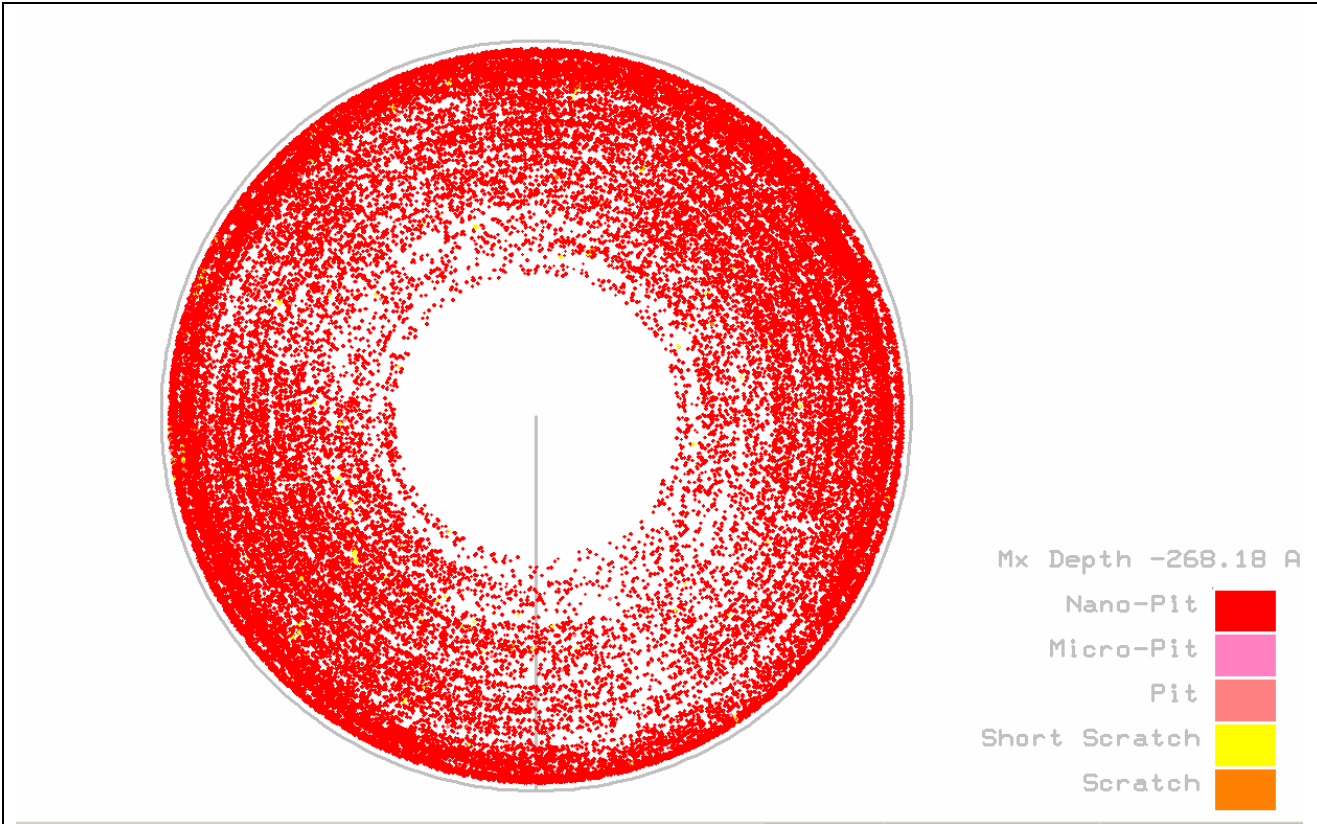
Nano-Pit Nano-Scan with Defects Deeper than 48 Angstroms



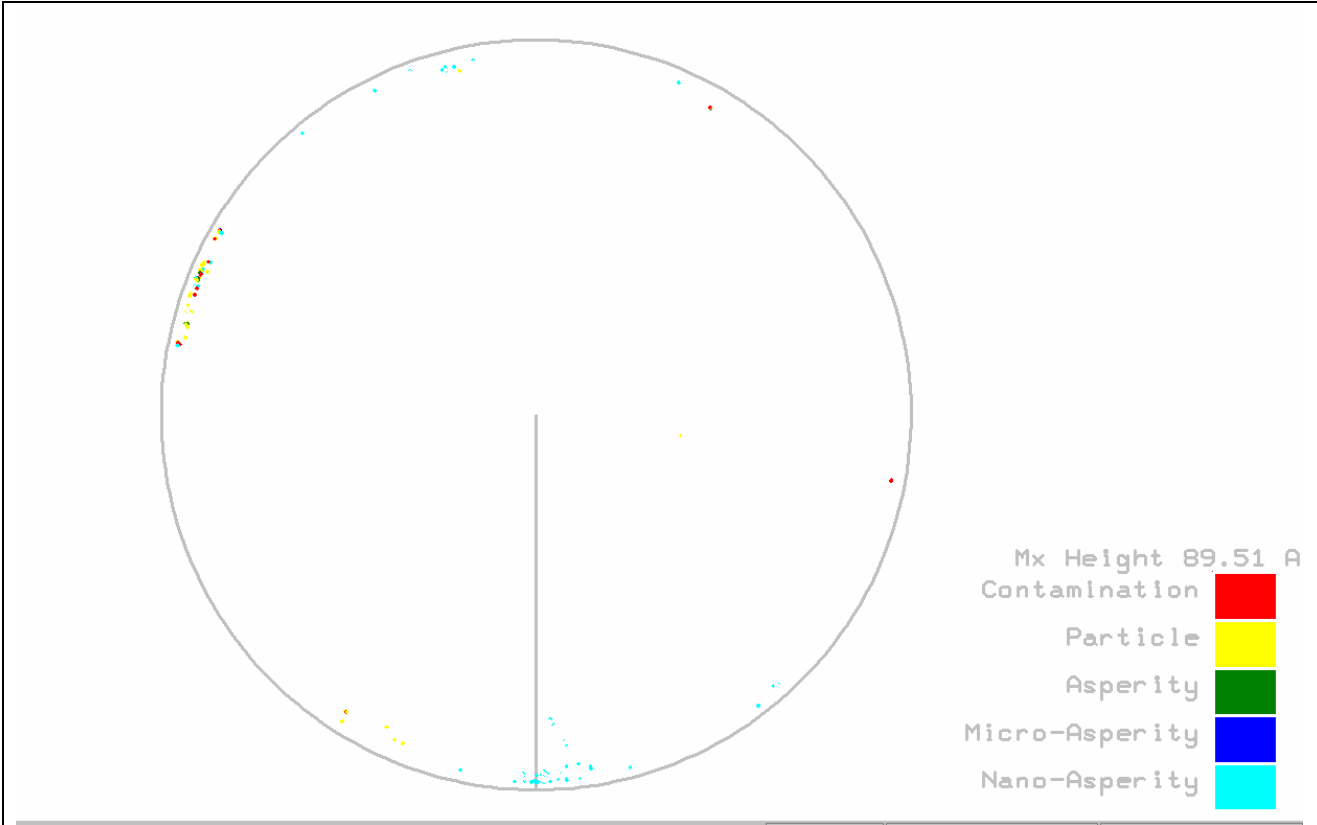
Nano-Pit Nano-Scan with Defects Deeper than 45 Angstroms



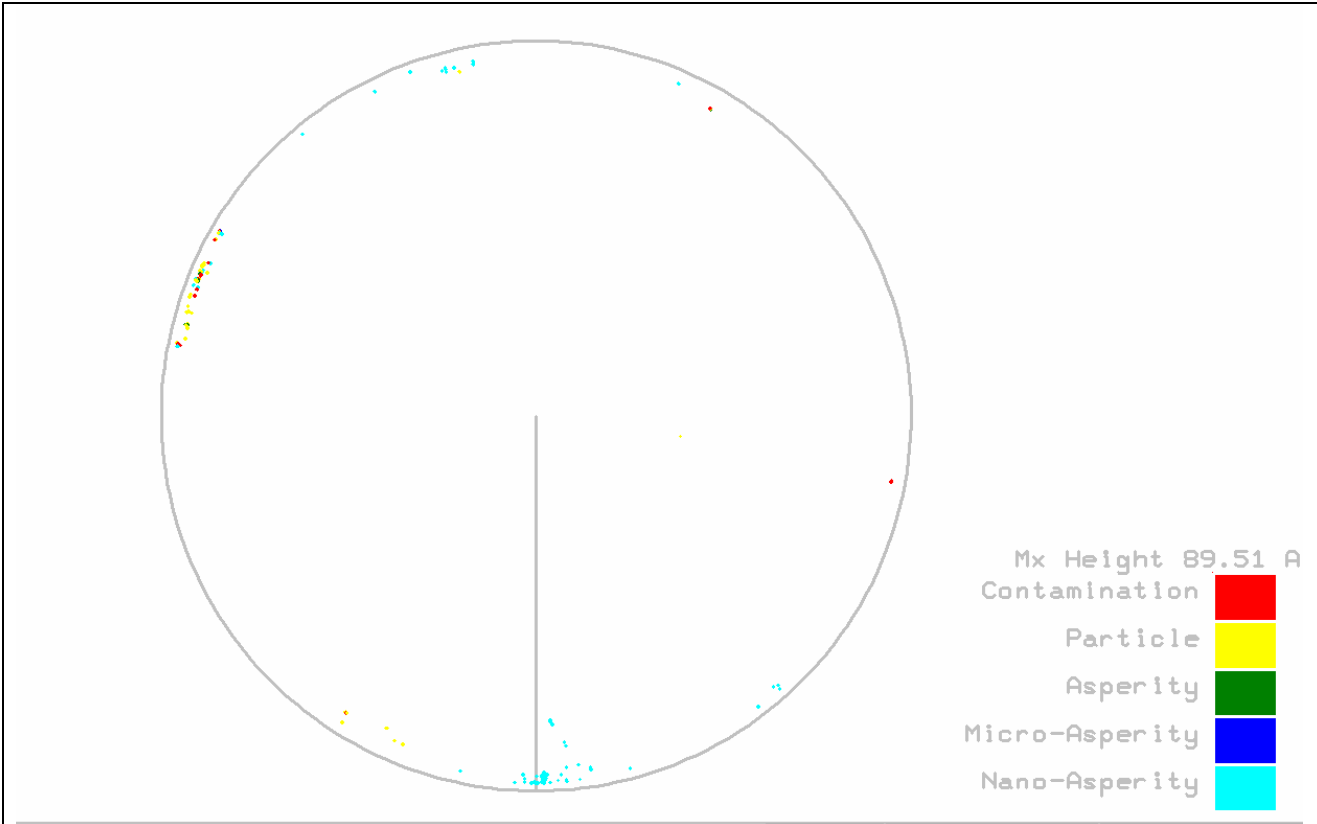
Nano-Pit Nano-Scan with Defects Deeper than 42 Angstroms



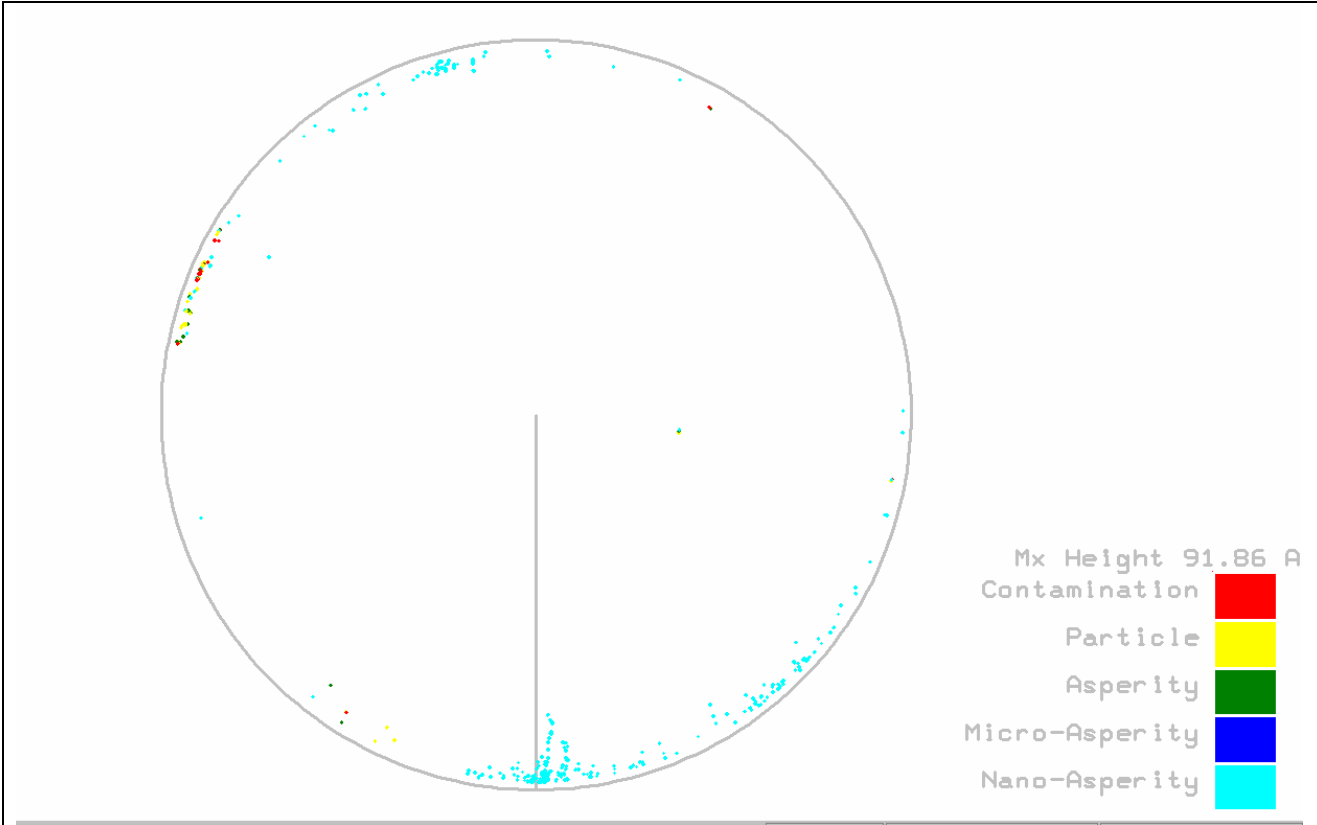
Nano-Pit Nano-Scan with Defects Deeper than 39 Angstroms



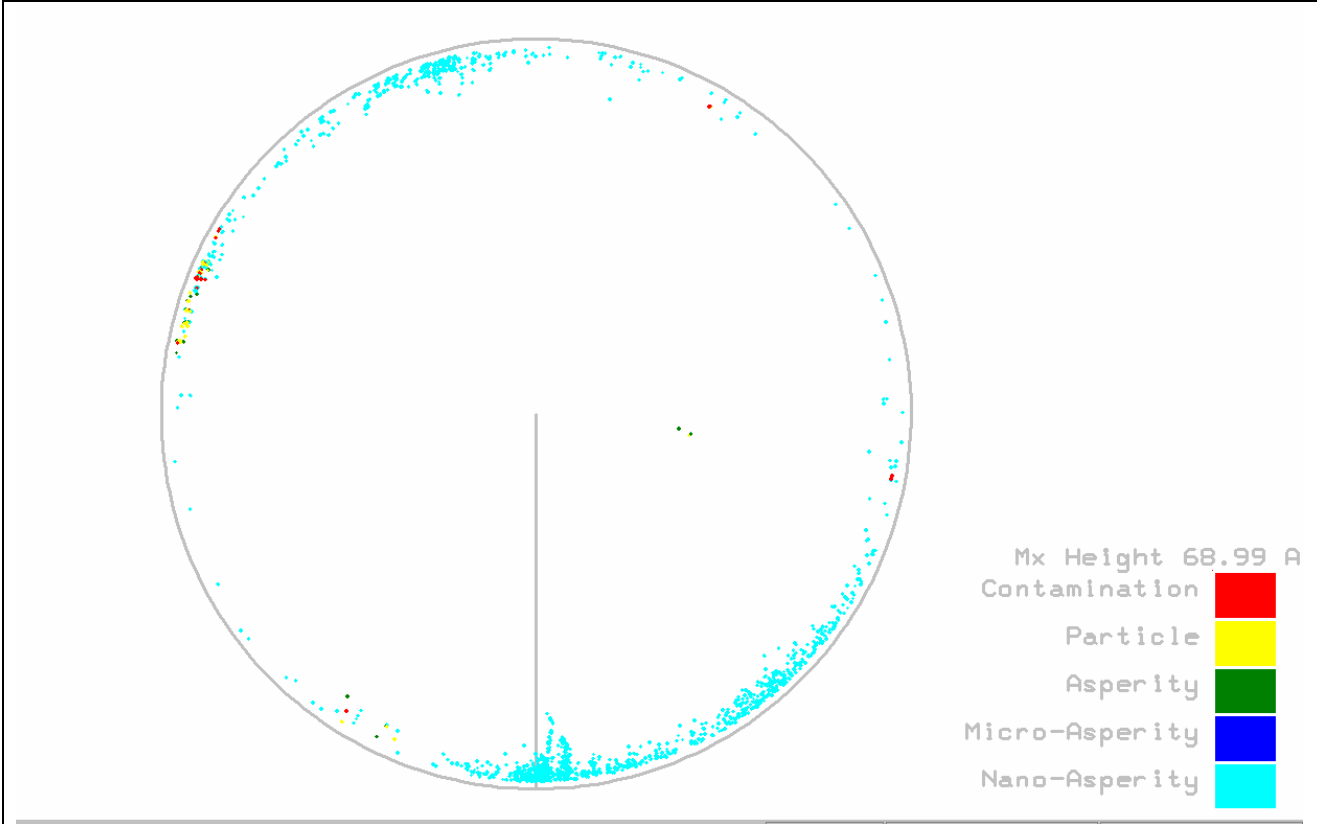
Nano-Asperity Nano-Scan with Defects Higher than 60 Angstroms



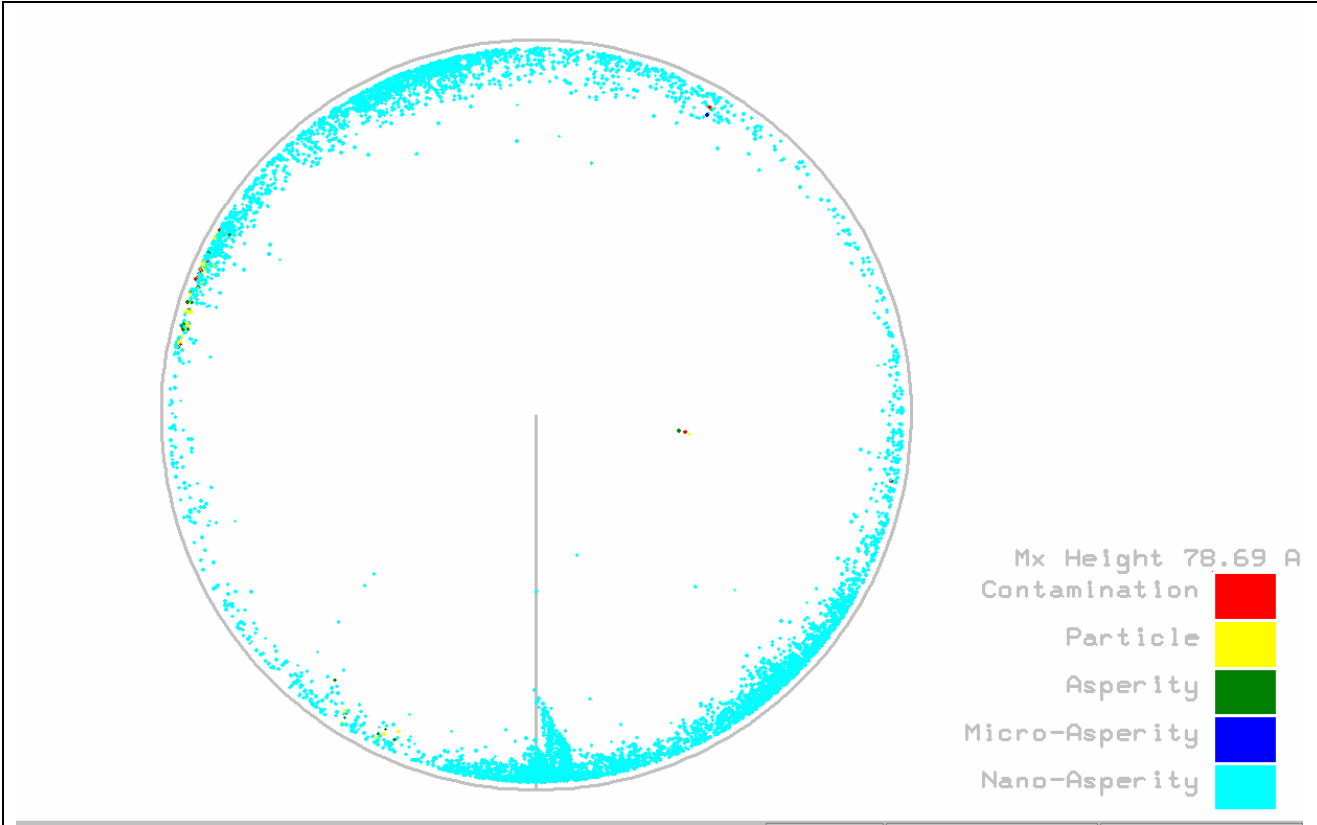
Nano-Asperity Nano-Scan with Defects Higher than 55 Angstroms



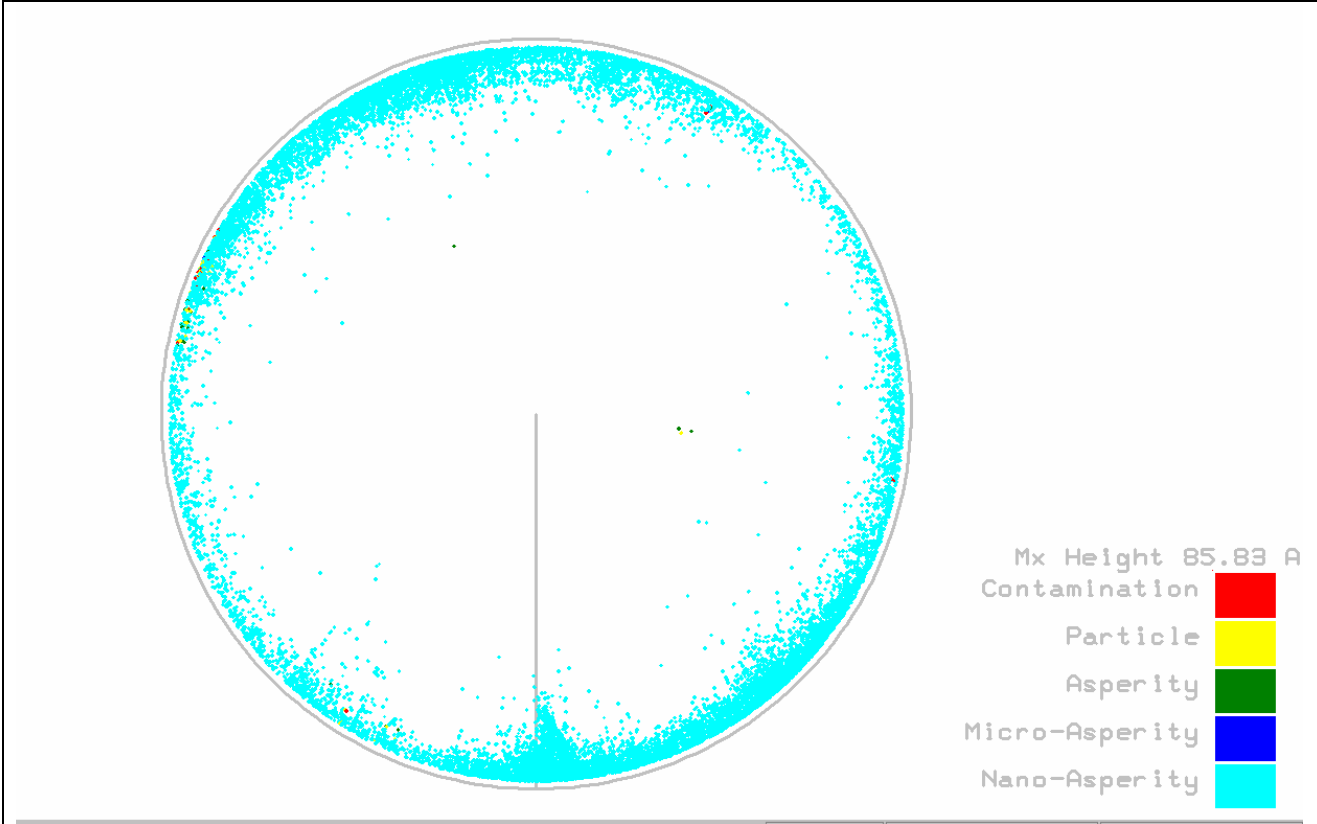
Nano-Asperity Nano-Scan with Defects Higher than 50 Angstroms



Nano-Asperity Nano-Scan with Defects Higher than 45 Angstroms



Nano-Asperity Nano-Scan with Defects Higher than 40 Angstroms



Nano-Asperity Nano-Scan with Defects Higher than 35 Angstroms